

Ch. Arrell: Aramis spectral diagnostics - update

Report of Contributions

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As a barometer of SwissFEL performance, high-fidelity spectral diagnostics offer a uniquely broad measure of photon output. This presentation will review recent enhancements to the usability, signal fidelity, and measurement capabilities of the principal X-ray spectrometer for Aramis - the PSSS. We will discuss improvements in measuring a wider spectral bandwidth in the hard X-ray range and the provision of single-shot tender X-ray spectral data via the 3rd harmonic. Finally, we will explore various online analysis tools and discuss the valuable insights they offer for assessing machine performance through their data.

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Session Classification: Focus report